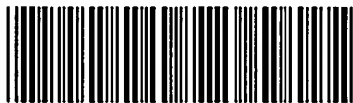


**Search Notes**

Application/Control No.

10/067,304

Examiner

Ba Huynh

Applicant(s)/Patent under  
Reexamination

FUJII ET AL.

Art Unit

2179

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East: USpat, USpgpub, Epo, Jpo, Derwent, IBM-tdb files search updated	6/24/2006	HB